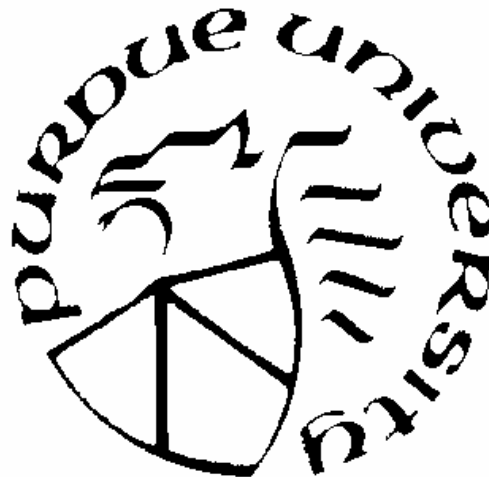


Emergence Uniformity in Corn: Is it Essential for Ear Size Consistency and Improved Yield?

Tony J. Vyn

**Graduate Students: Mercedes Murua, Missy Bauer,
Ann Kline, Jason Brewer and Martin Gonzalo**

Agronomy Department, Purdue University





Accepted Hypothesis:

Delayed Seedling Emergence



Shorter Plants



↑ Delayed Silk Emergence

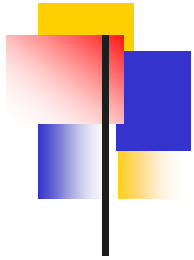


↑ Delayed Maturity



Smaller ears at harvest





Previous Research on Emergence

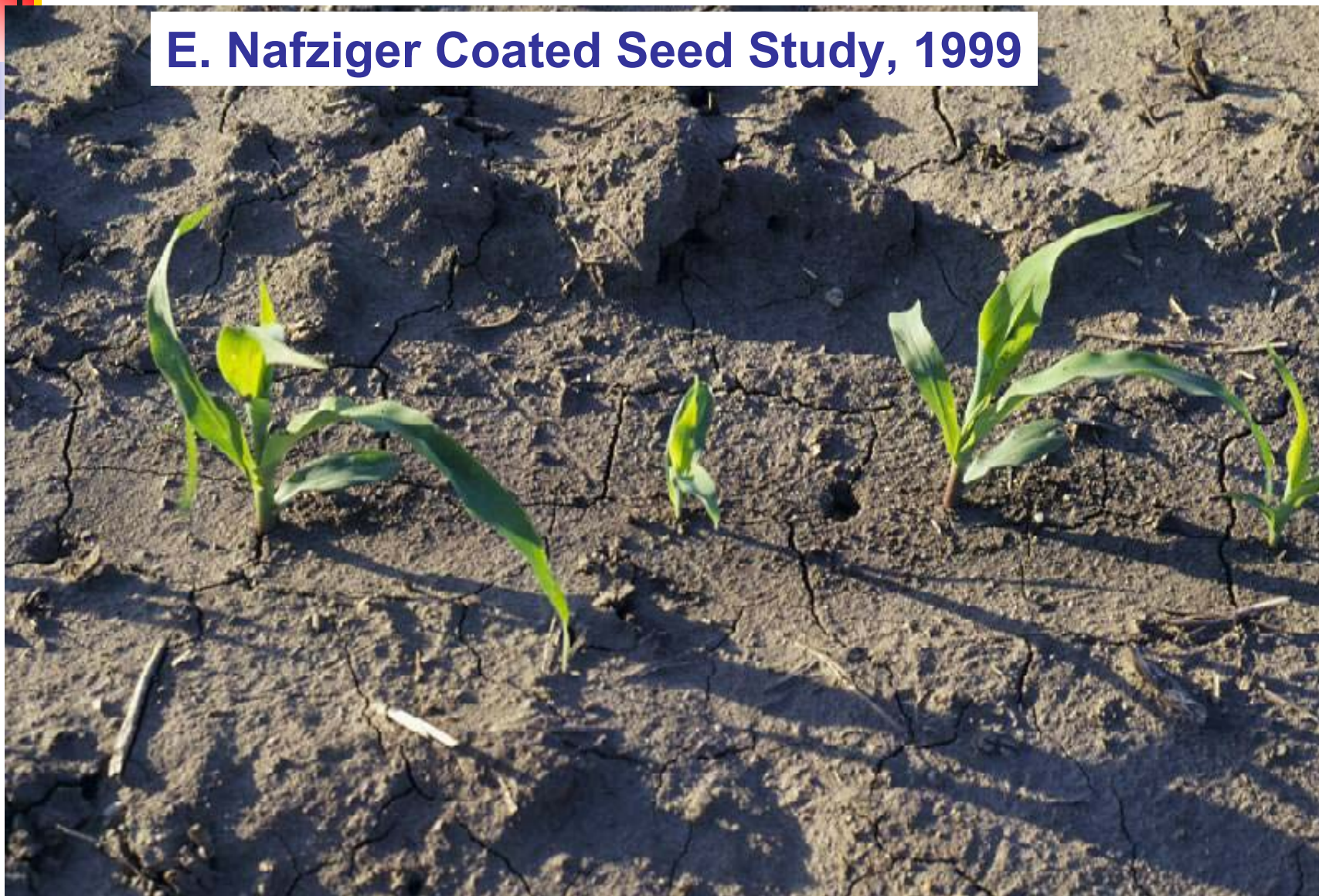
- Part of the stand planted 7-21 days later ↓ Yield 5-22%



Source: Nafziger *et al.* (1991), Ford & Hicks (1992)

- Effects of Emergence variability amongst plants planted on the same day ??????

E. Nafziger Coated Seed Study, 1999



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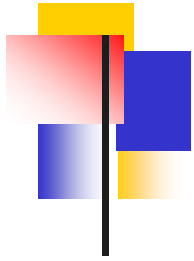
Yield Evaluation in Research?



Plot Combine

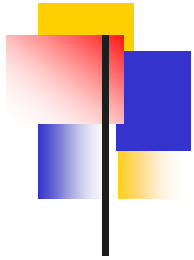


Individual Plant?

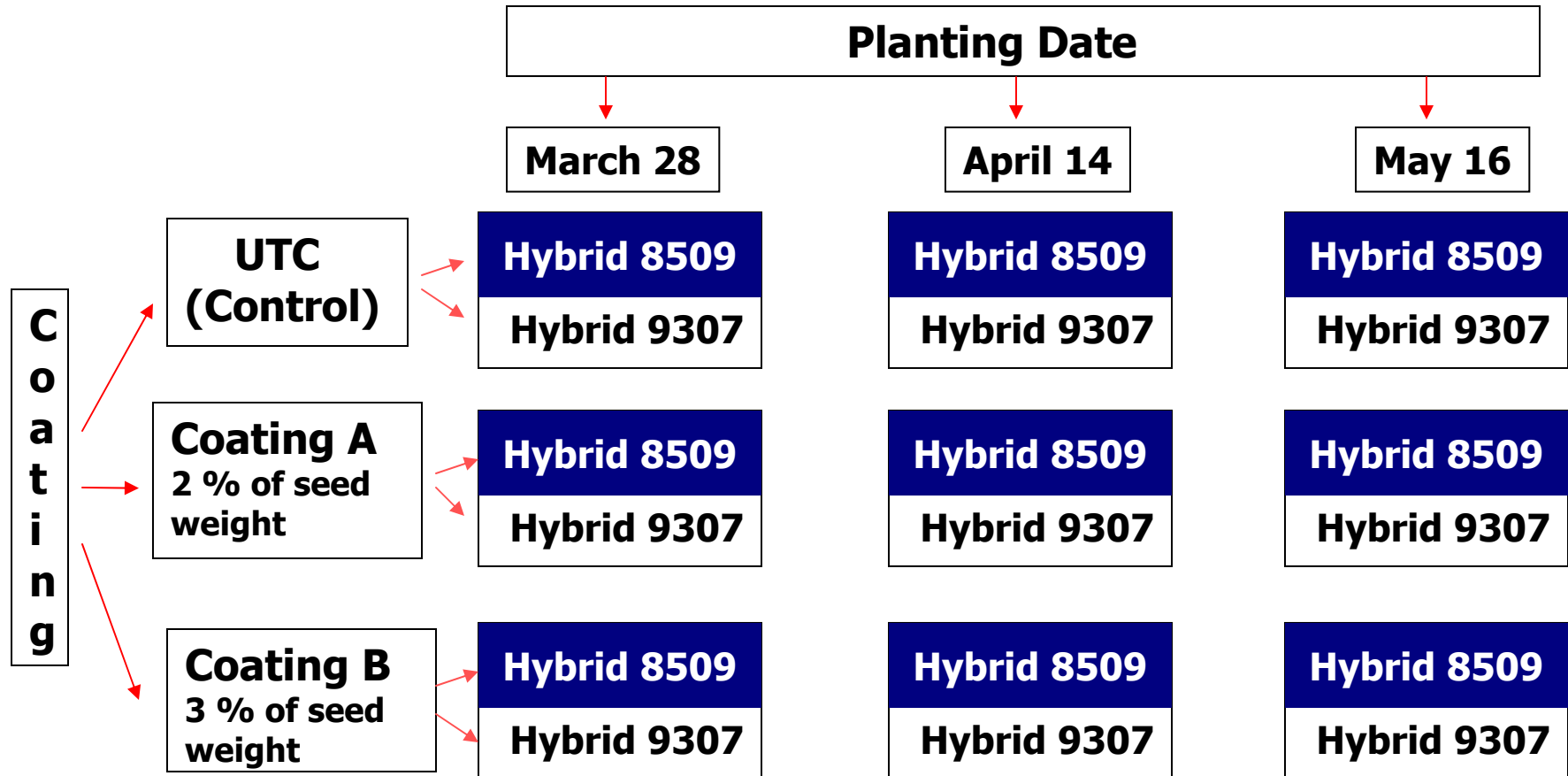


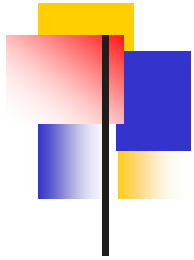
Experimental Design & Methodology (2000-2001)

- **Design:** Split-plot design, 4 replications
- **Soil:** Drummers, silty clay loam, 3 to 4.5 % O.M.
- **Tillage System:** No-till
- **Rotation:** Corn/soybeans
- **Hybrids:** Fielder's Choice 9307 & 8509 (106 and 109 days RM)
- **Planting Population:** 80,000 seeds/ha

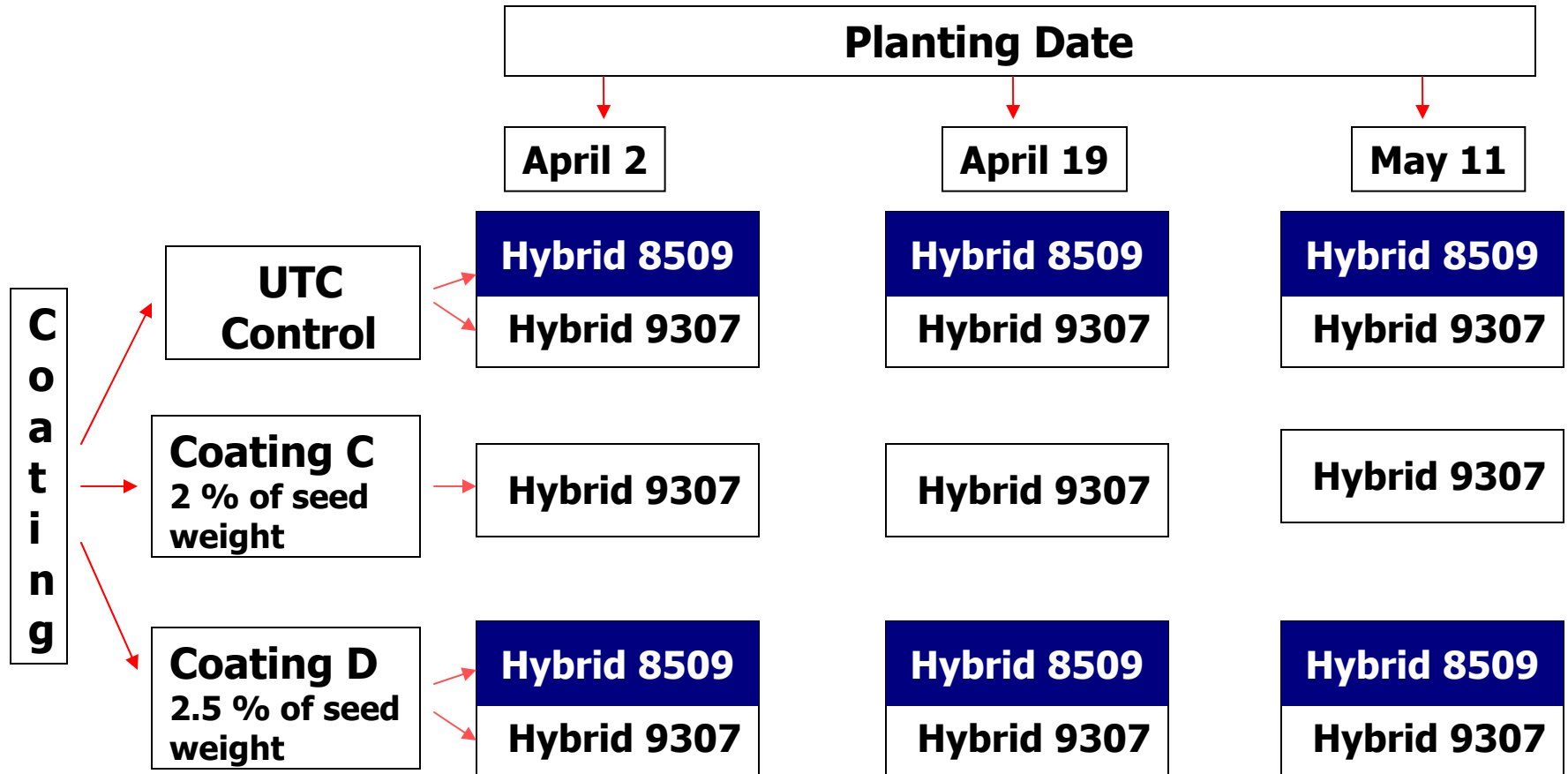


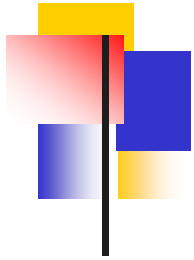
Experimental Design in Year 2000





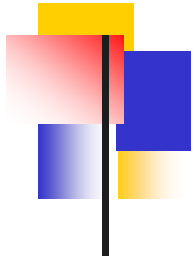
Experimental Design in Year 2001



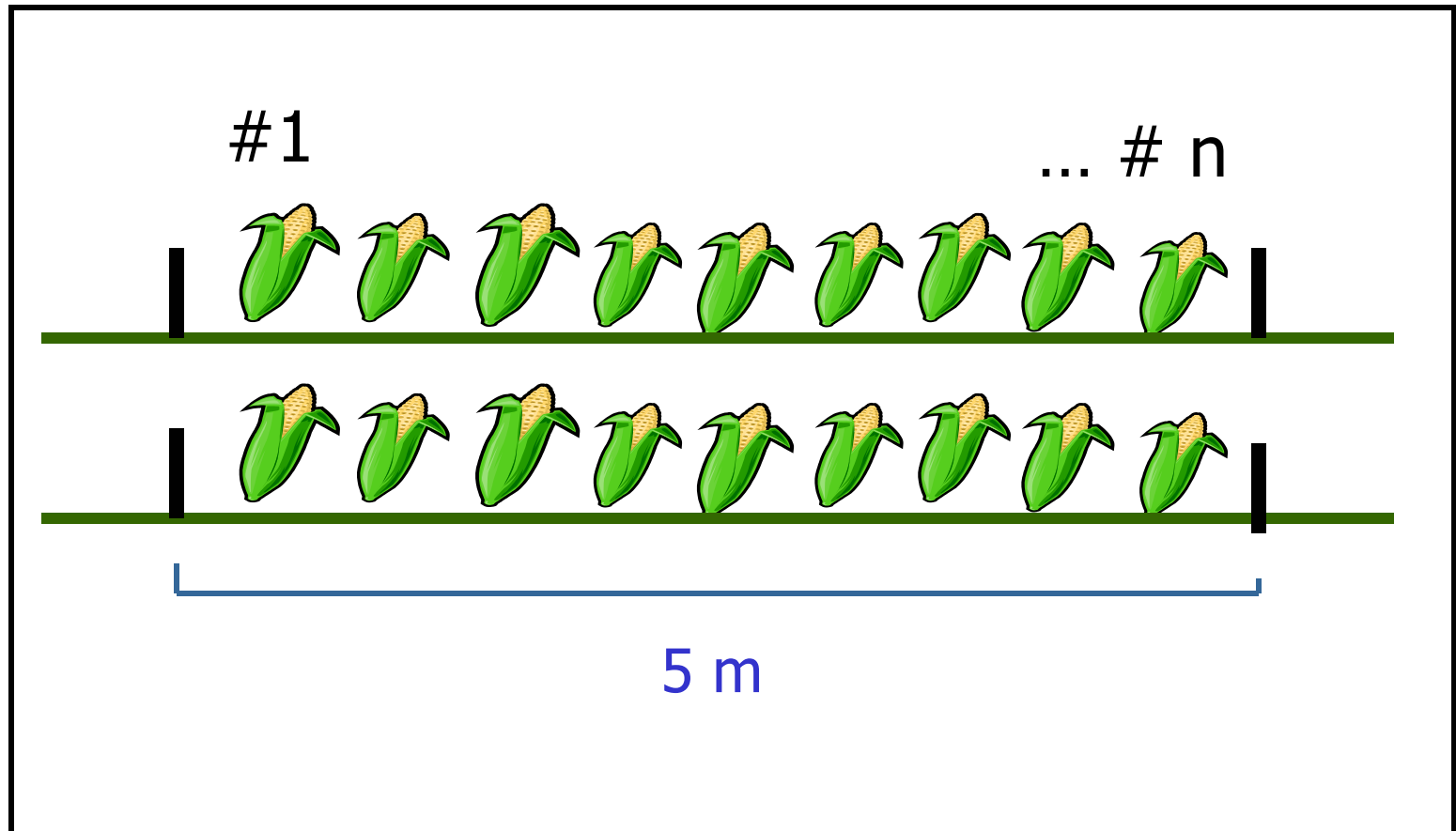


Measurements

- Daily emergence counts (0 to 100%).
- Plant populations (emergence & harvest).
- Plants heights and V-stages (4-6 & 6-8 weeks).
- Daily silk emergence (0 to 100 %).
- Grain yield.

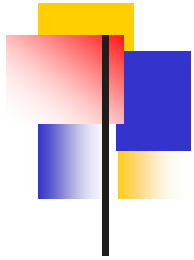


Measurements



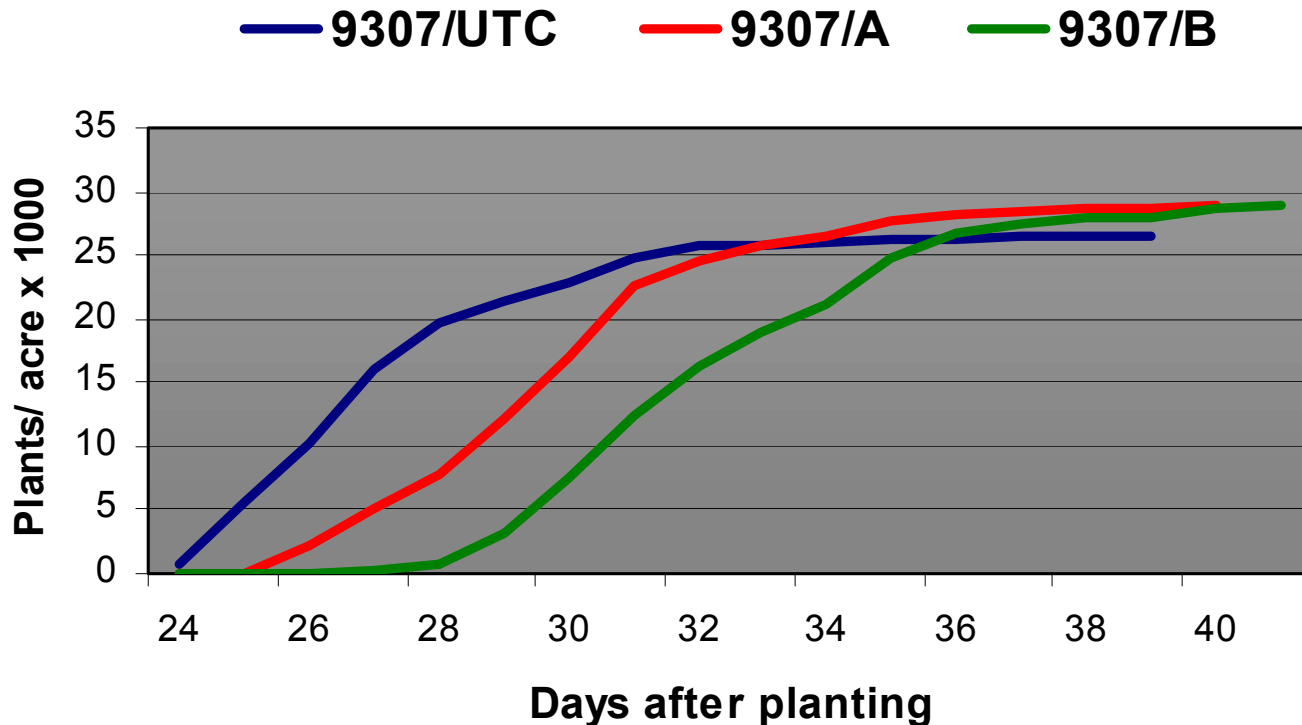
Results



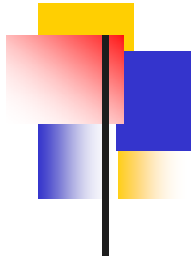


Emergence Profile

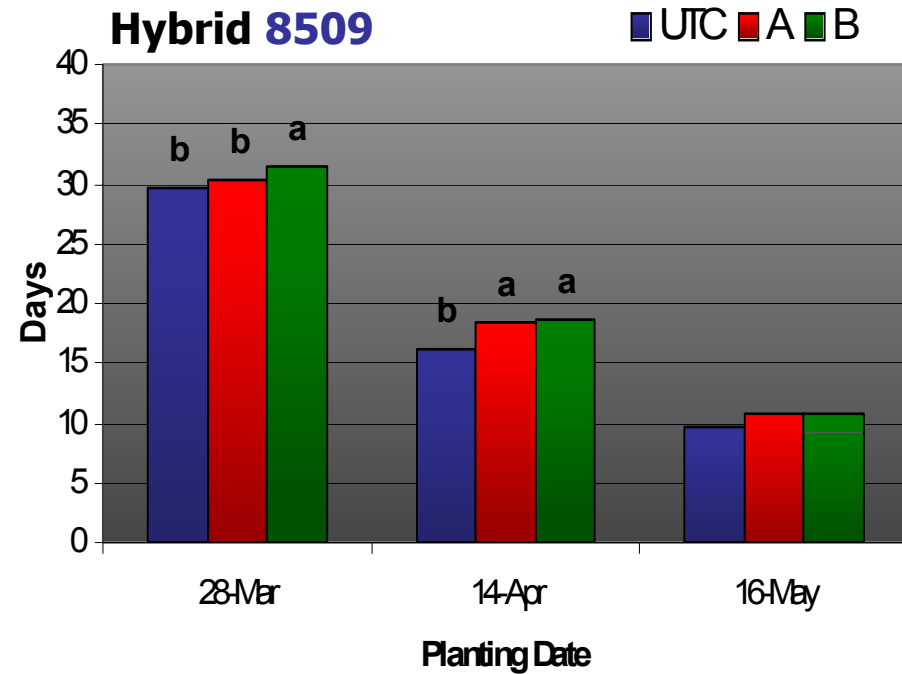
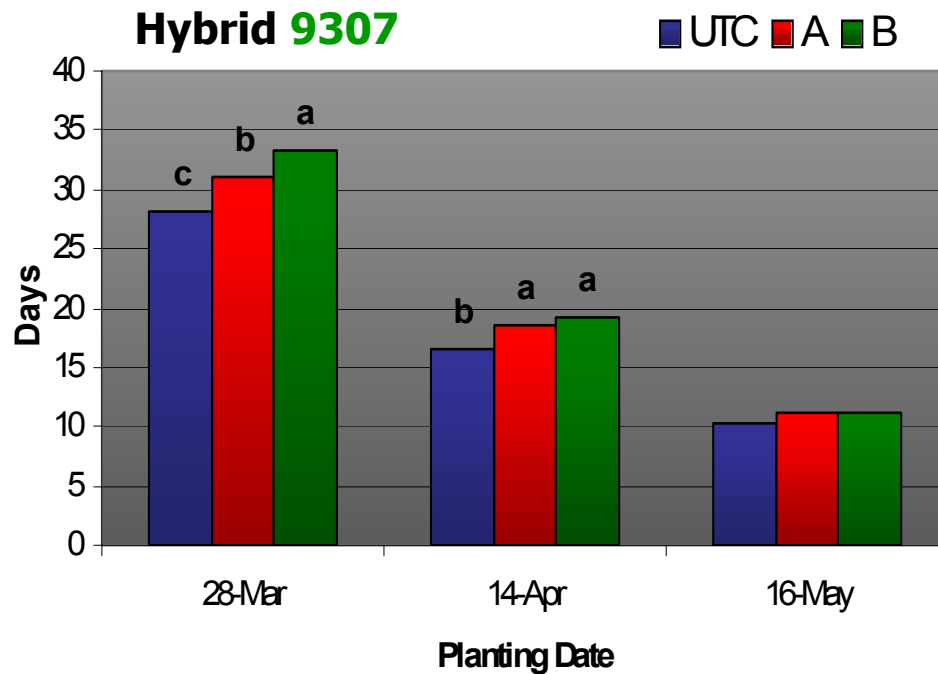
Planting Date: March 28, 2000

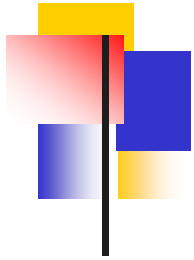


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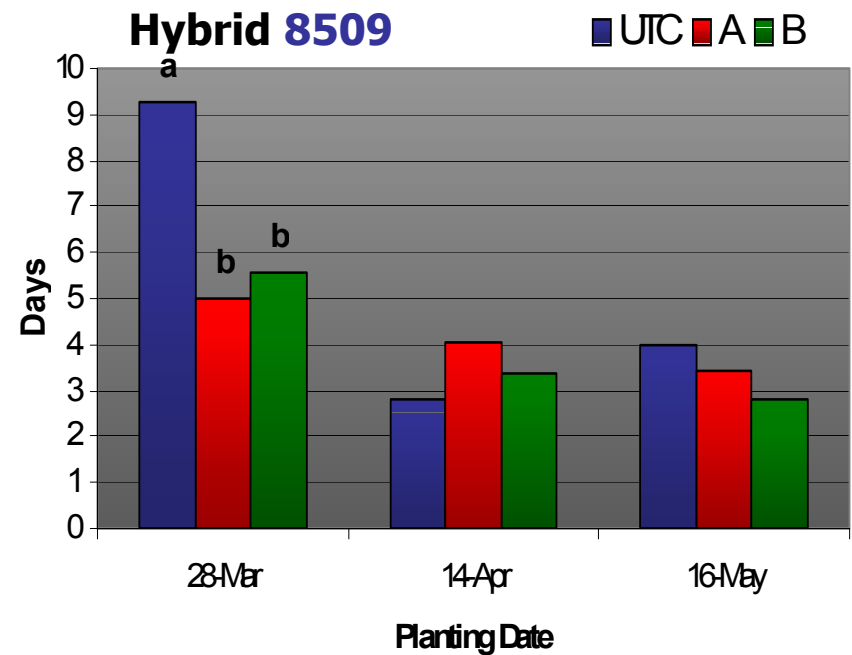
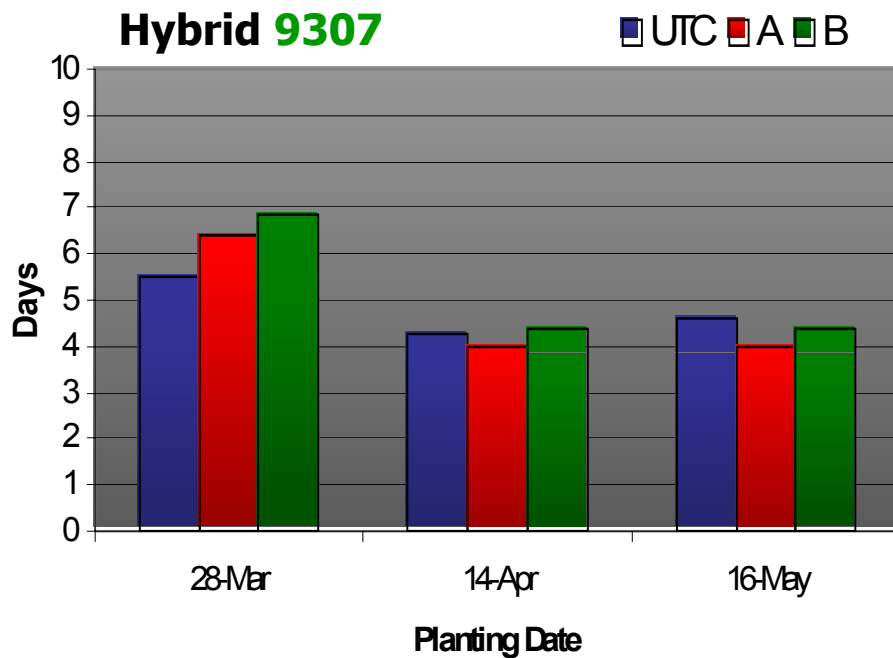


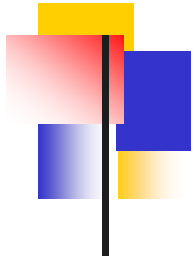
Days to 50% Emergence in 2000



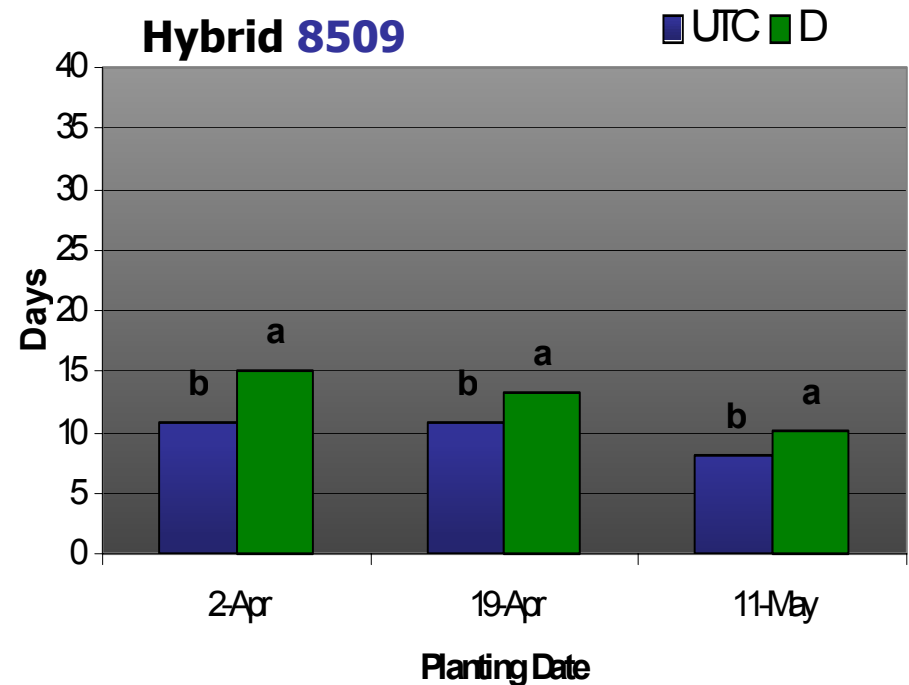
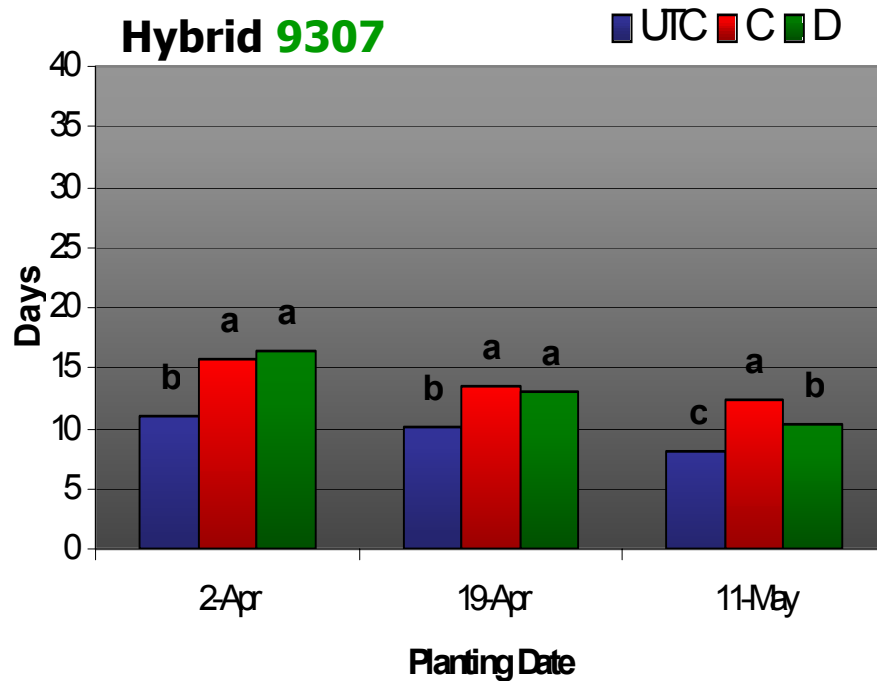


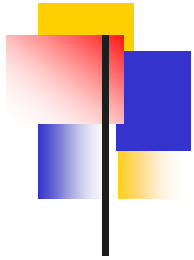
Days from 10 to 90 % Emergence in 2000



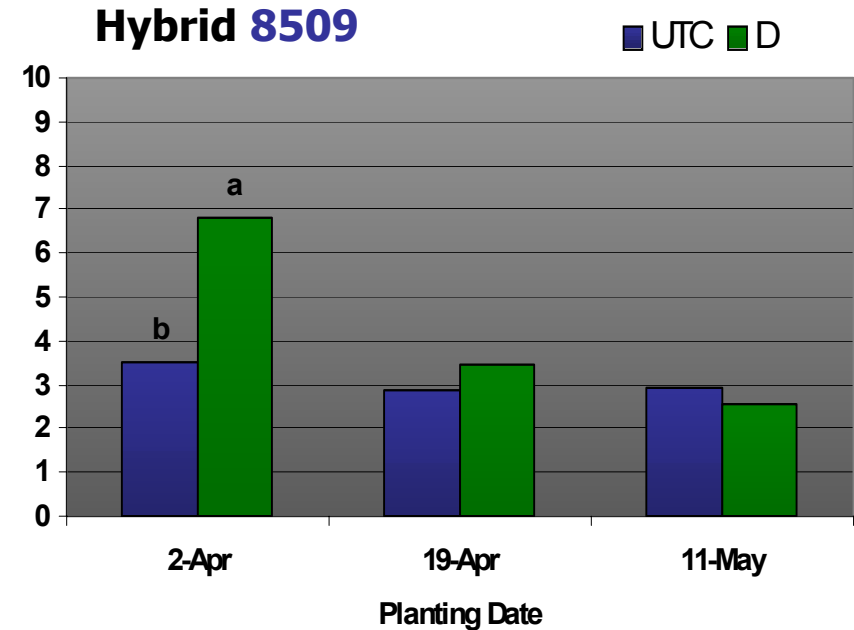
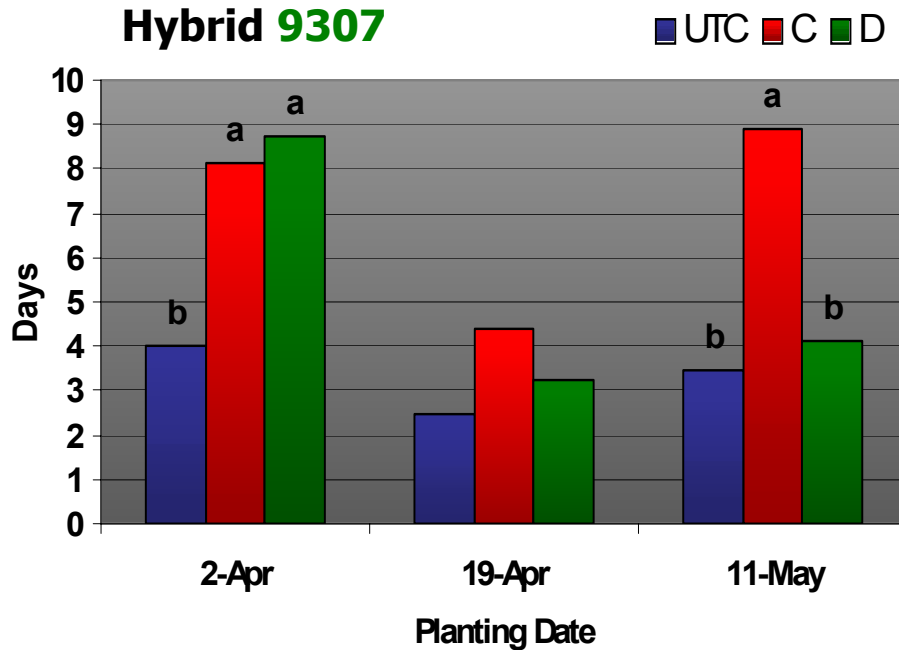


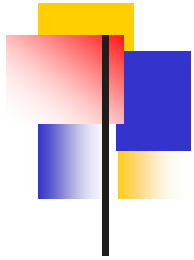
Days to 50% Emergence in 2001



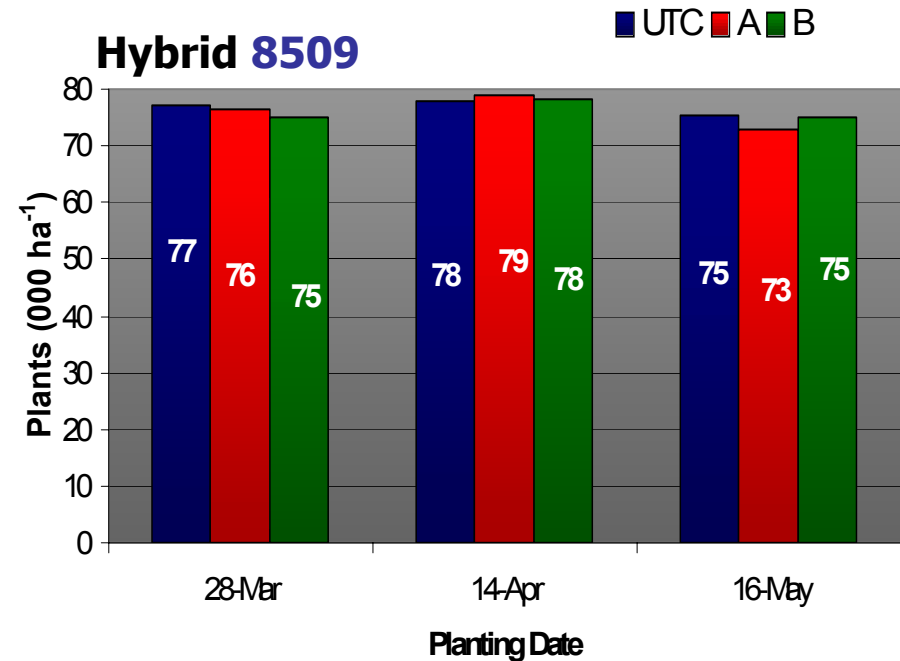
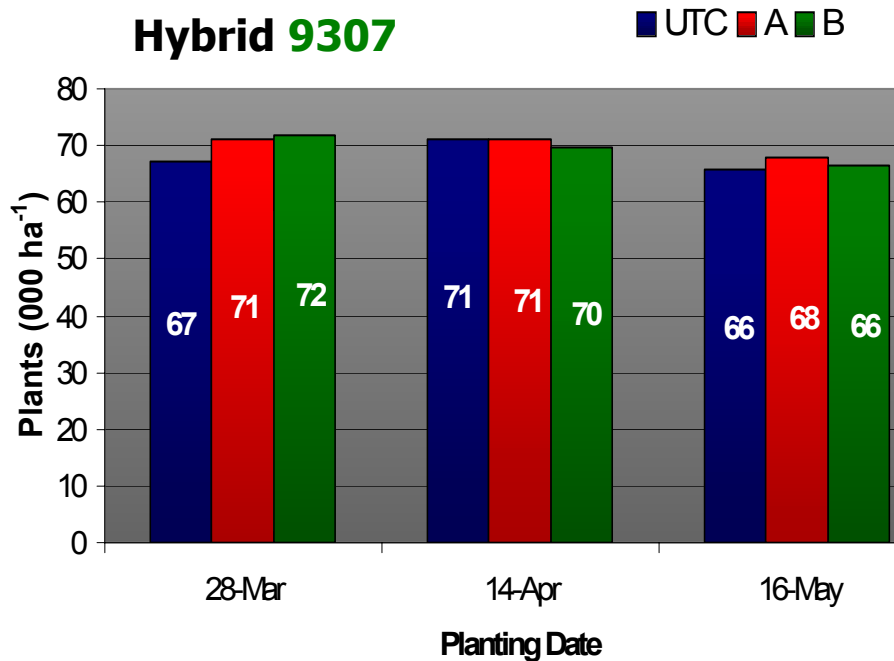


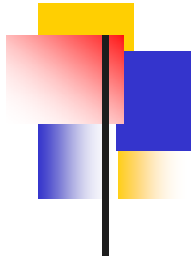
Days from 10 to 90 % Emergence in 2001



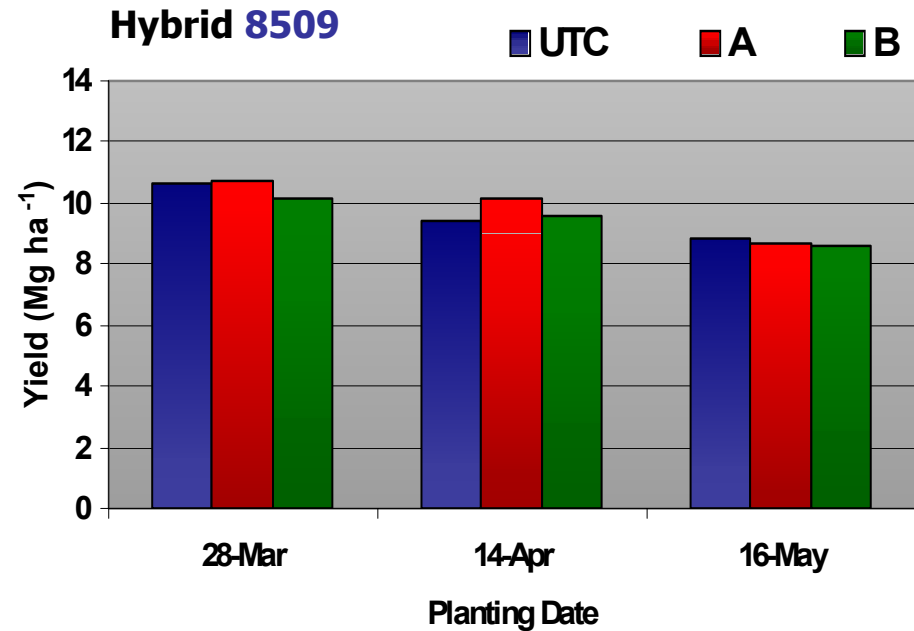
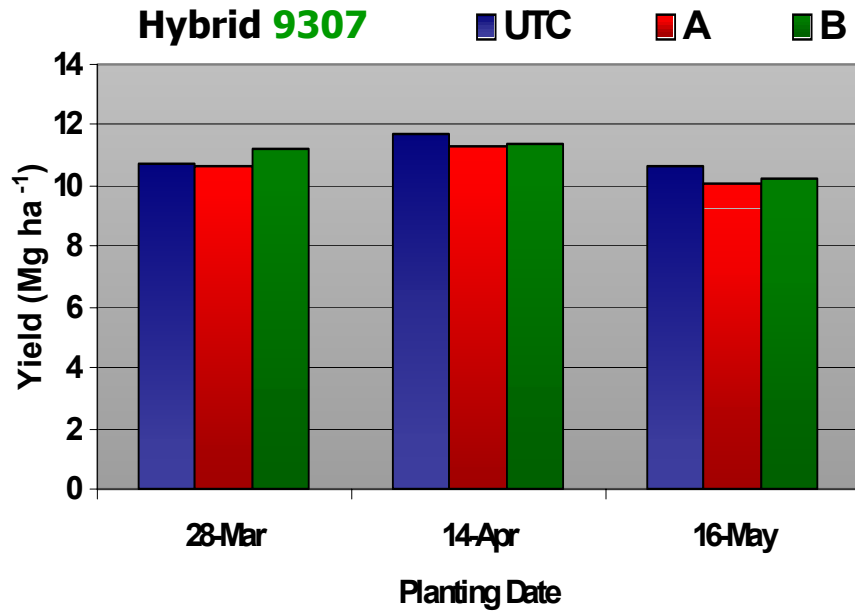


Population after complete emergence in 2000



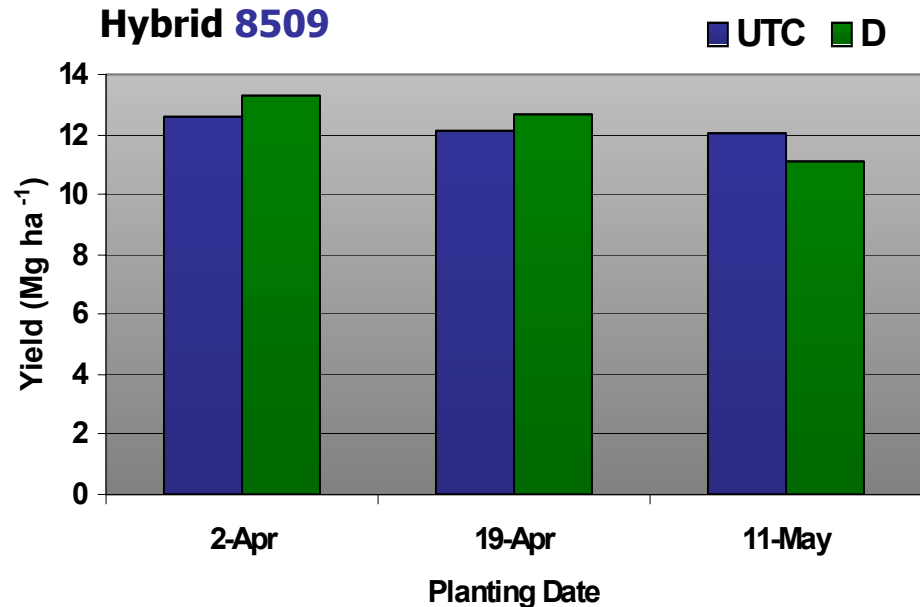
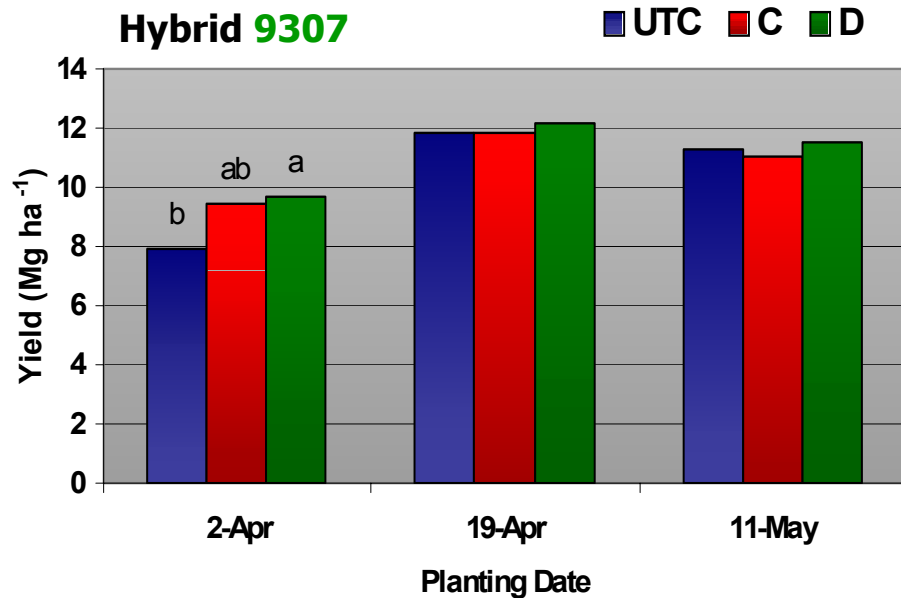


2000 Grain Yields





2001 Grain Yields



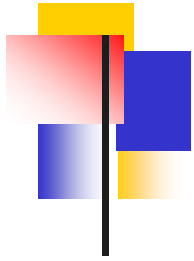
Treatment Comparisons

Significance

	<u>Within Hybrid 9307</u>	<u>Within Hybrid 8509</u>
PD 1 (C) vs PD 2 (UTC)	**	NA
PD 1 (D) vs PD 2 (UTC)	*	NS
PD 1 (UTC) vs PD 2 (UTC)	**	NS

*, ** significant at 0.05 and 0.01 probability levels, respectively.

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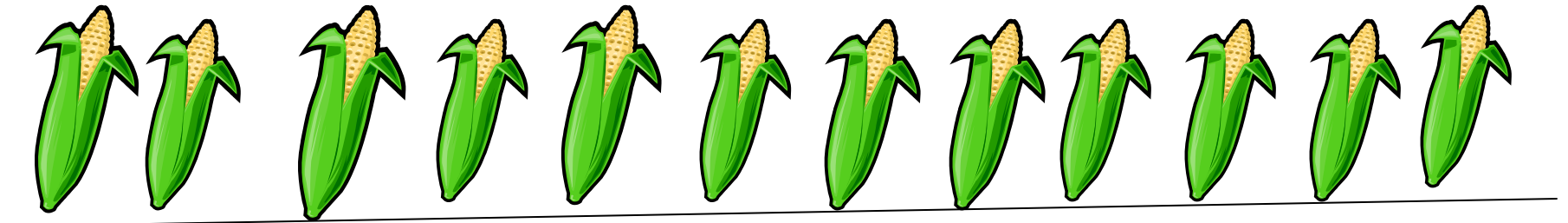


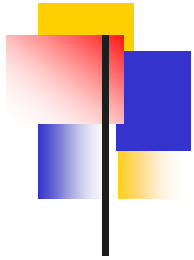
Analysis of Individual Plant Data

- 1 Simple Linear Regression per Plot:

2000 = 3 PD x 2 Hybrids x 3 Coat.Treat. x 4 Reps = **72 plots**

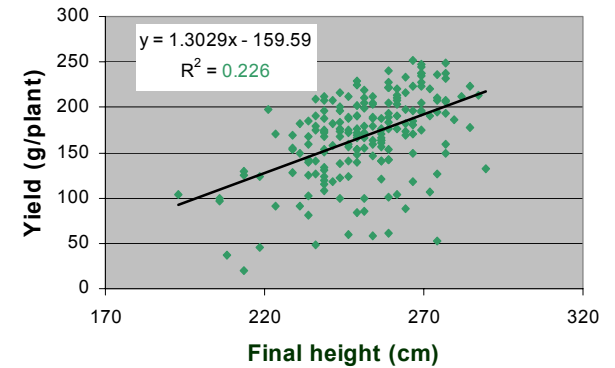
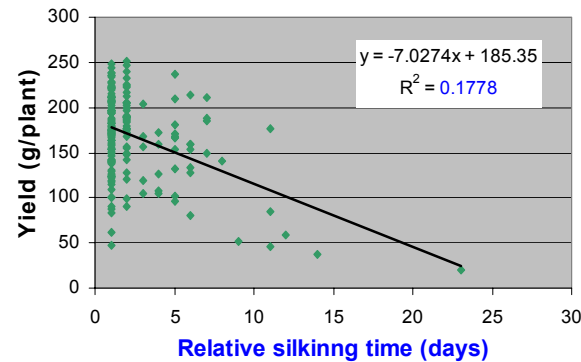
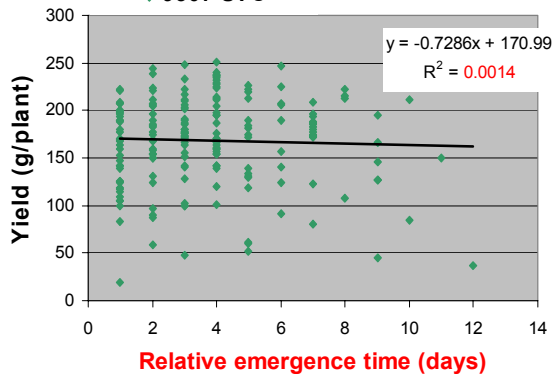
2001 = 3 PD x 5 Treat x 4 Reps = **60 plots**



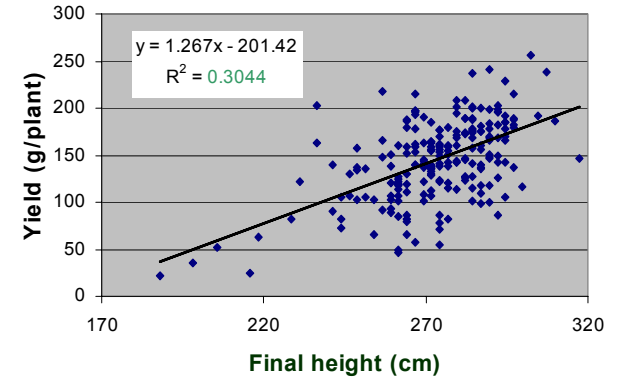
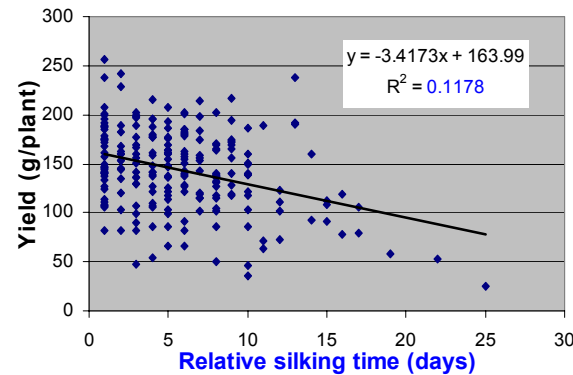
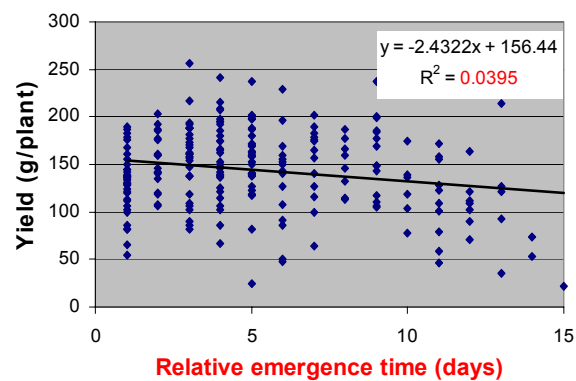


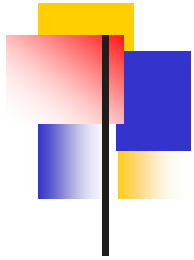
Linear Regressions of Individual Plant Yield for Early Planting in 2000

♦ 9307 UTC



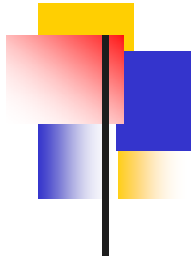
♦ 8509 UTC



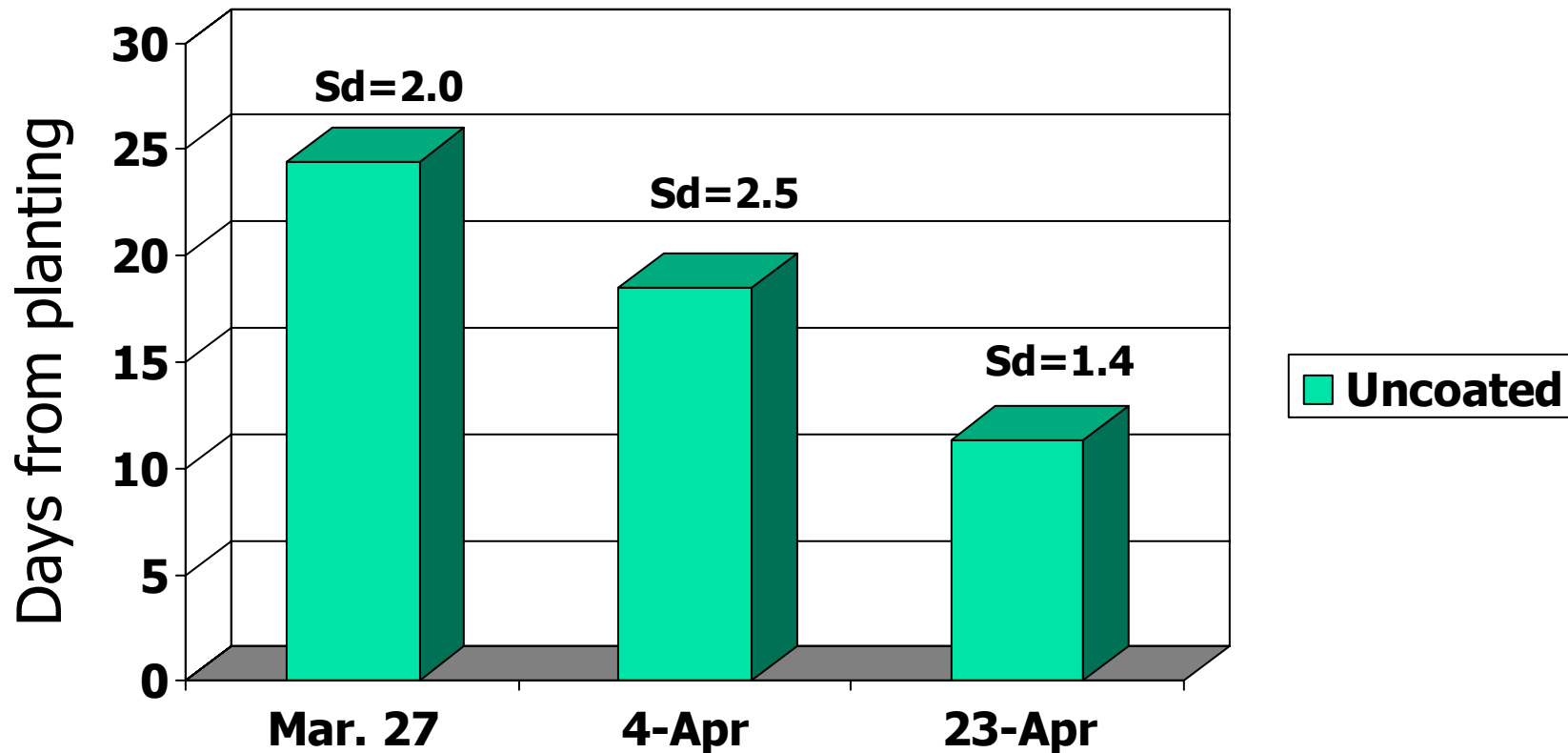


Yield as a function of "x" (2000-2001)

Independent Variable	Significant Regressions (%)		
	P value		
2000	0.01	0.05	0.1
Relative emergence time	13	24	28
Relative <u>silking time</u>	46	63	72
Final Height	60	71	74
2001			
Relative emergence time	10	13	18
Relative <u>silking time</u>	38	54	70
Final Height	32	47	52

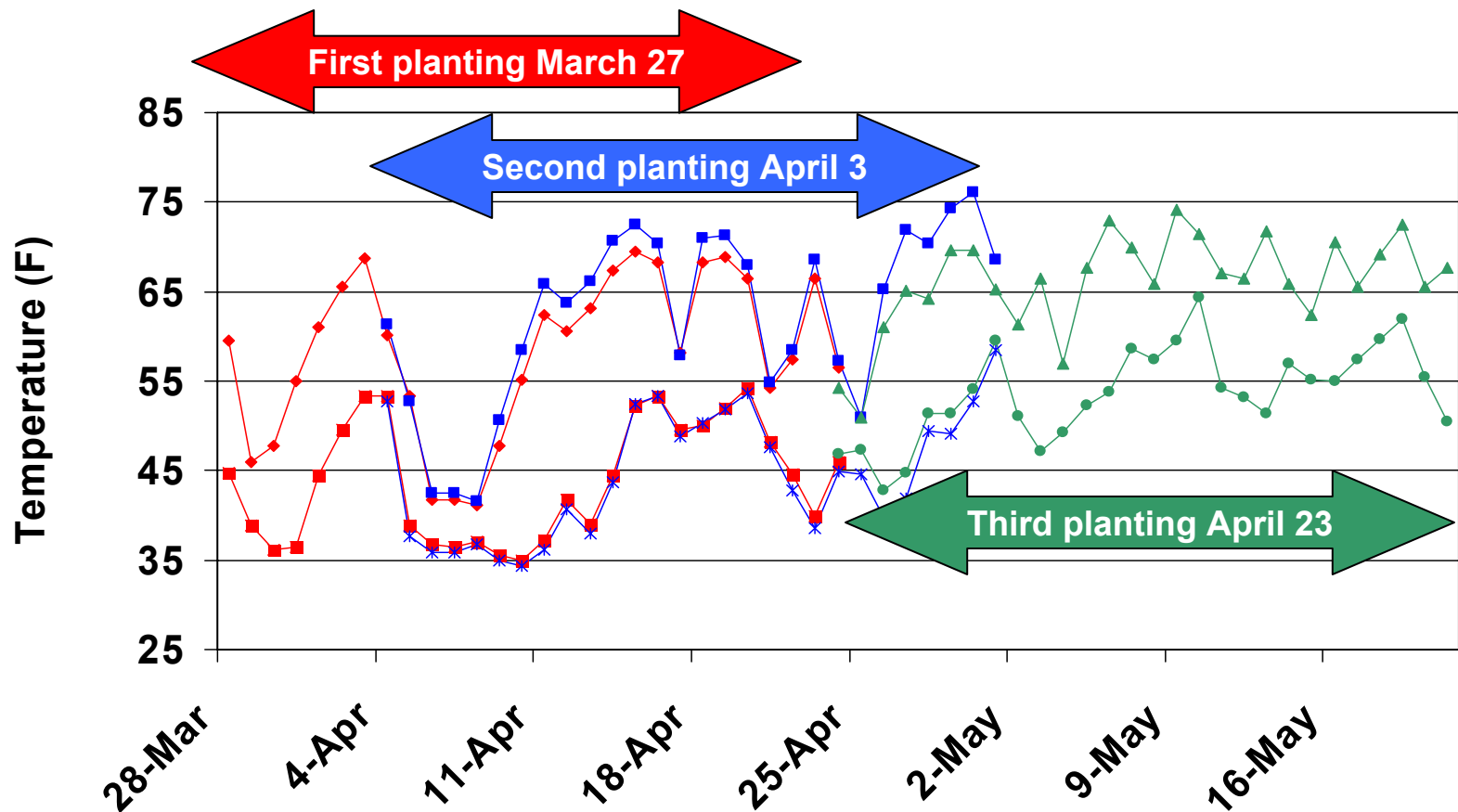


Emergence Time in 2003 (average of 3 hybrids at West Lafayette)

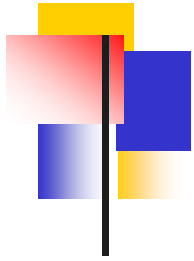


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Maximum and Minimum Soil Temperatures after Planting in 2003 (West Lafayette)

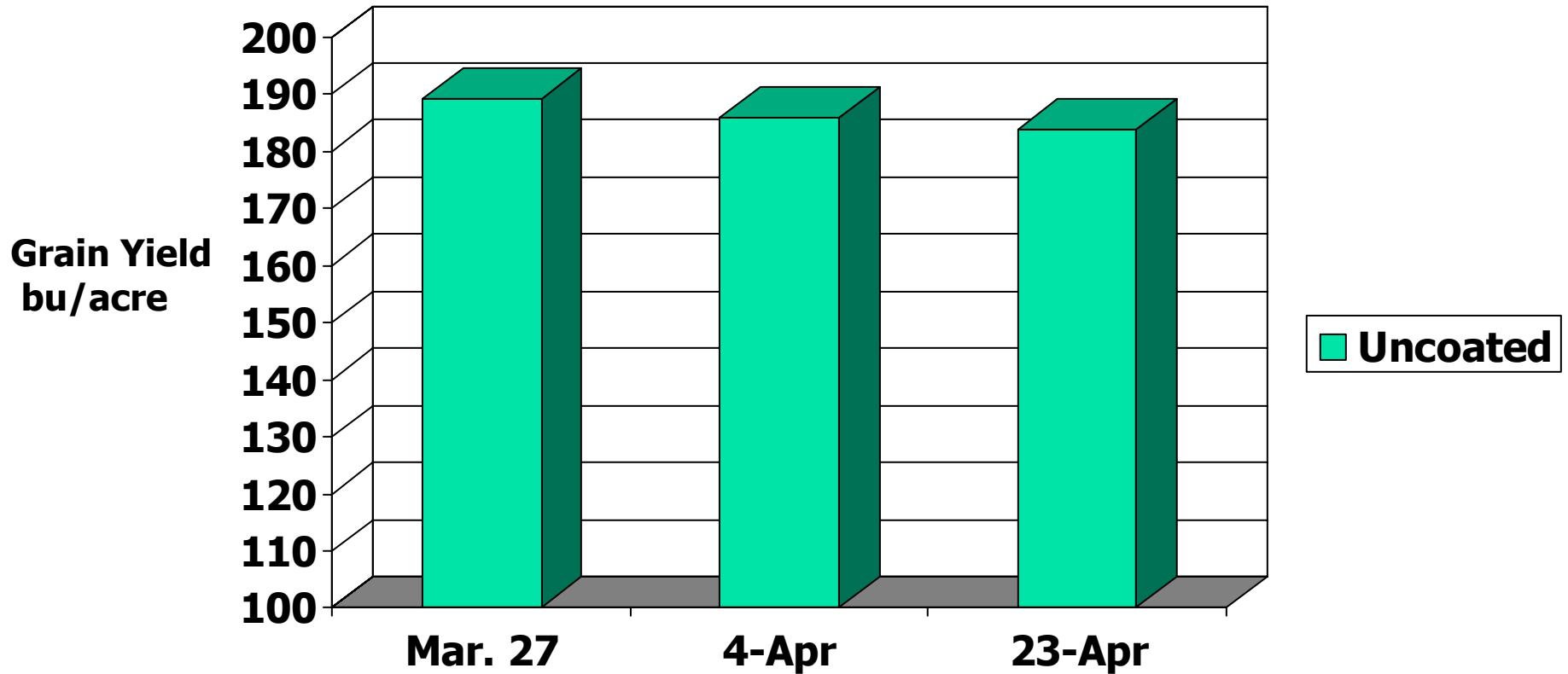


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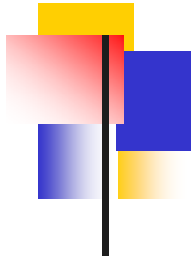


Planting Date Effects on Corn Yield in 2003

(mean of 3 hybrids at West Lafayette)



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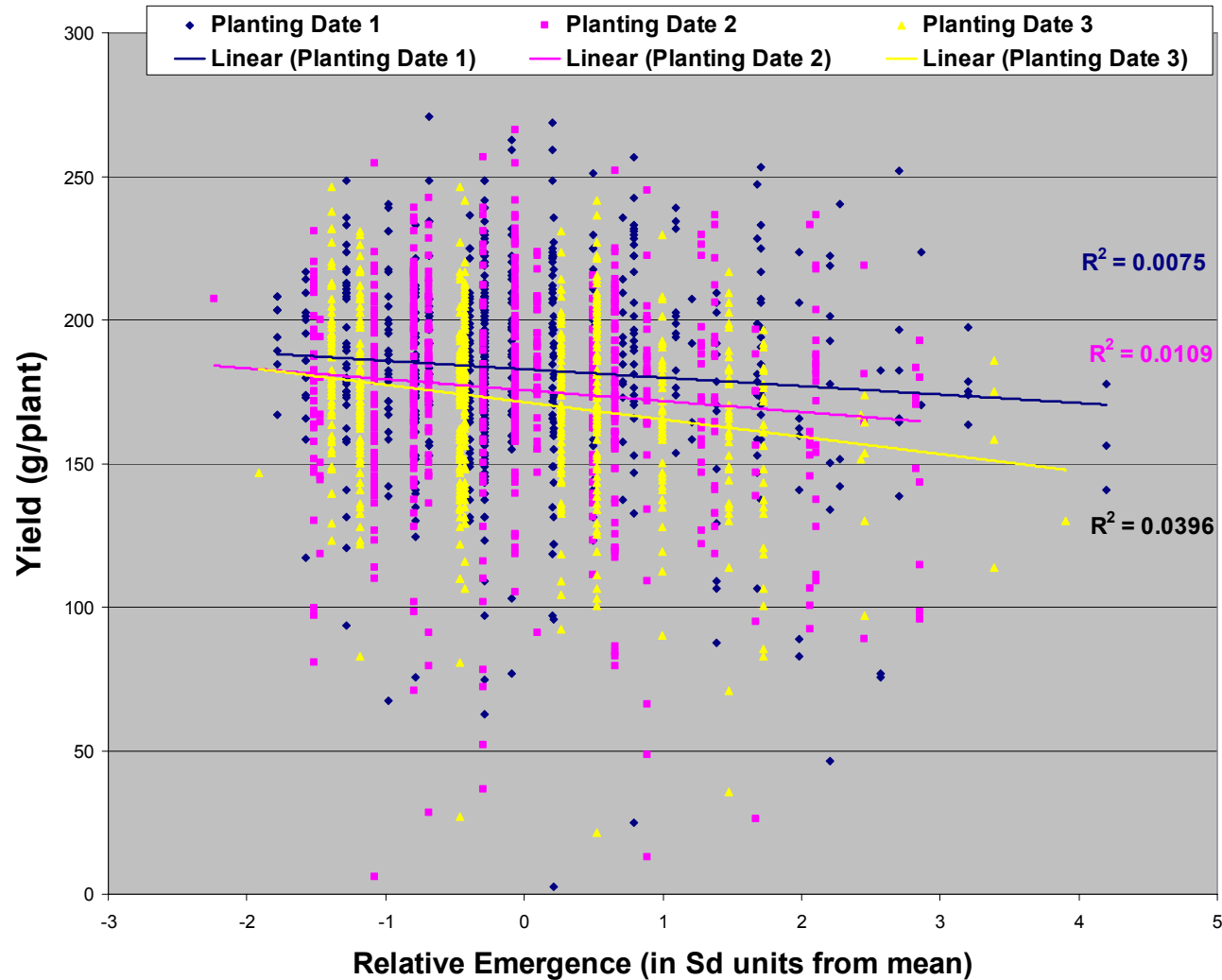


Relative Emergence for each Plant on each Planting Date

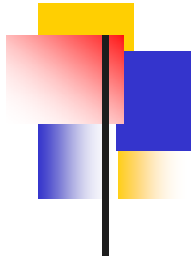
- Emergence Date for Plant – Mean for Emergence Date
Standard Deviation for Emergence



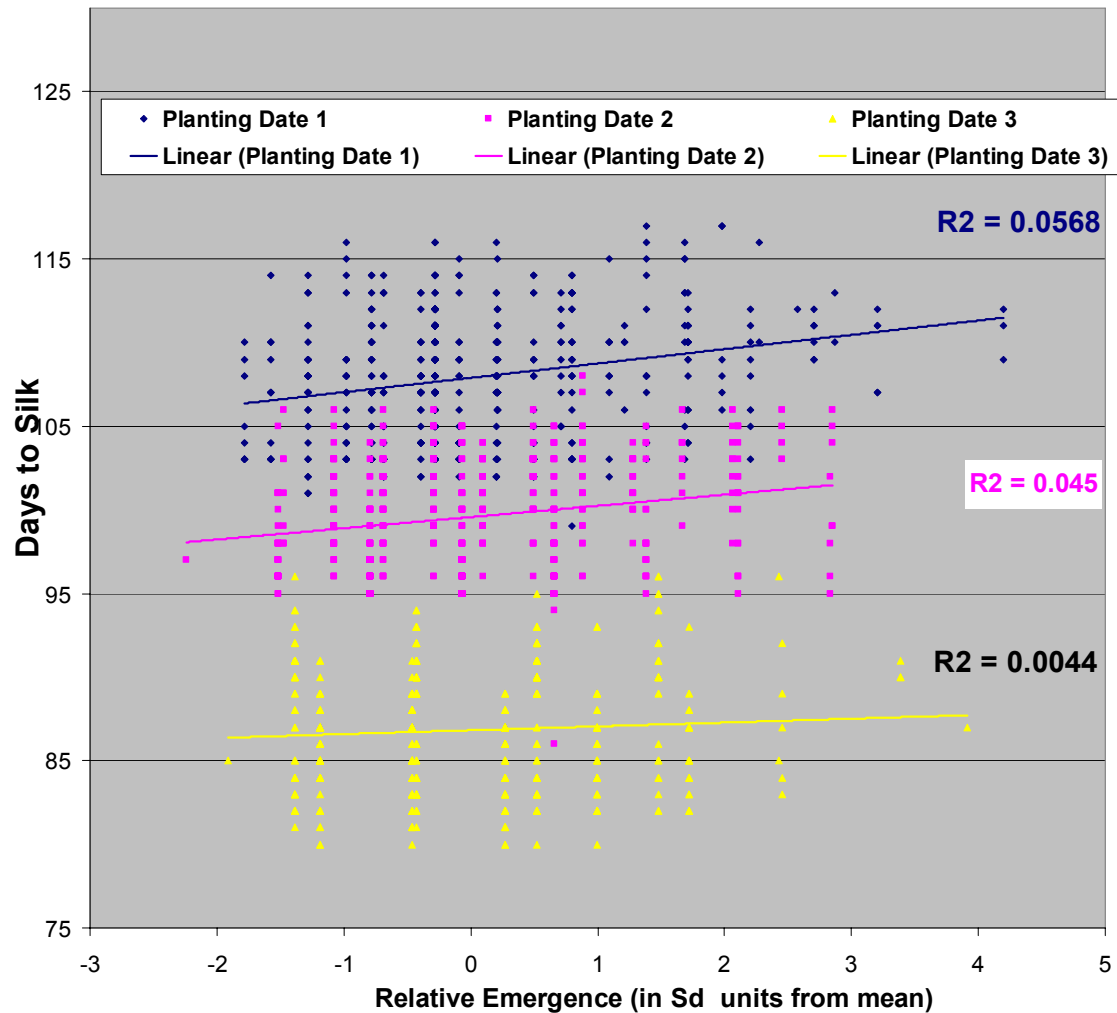
Ear Yield vs. Relative Seedling Emergence



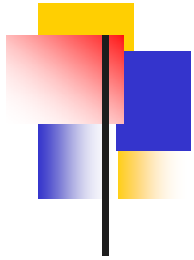
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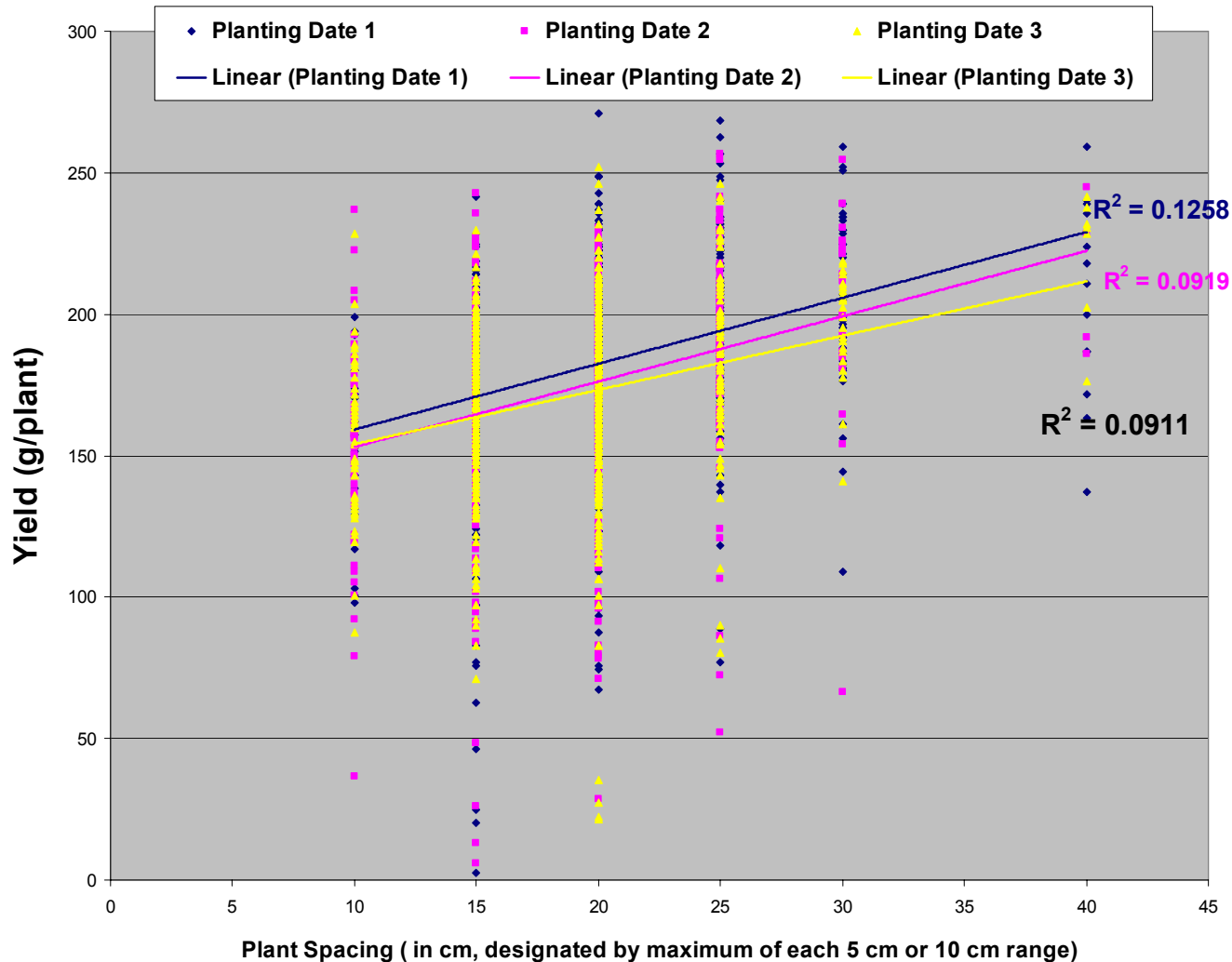
Time to Silking vs. Relative Seedling Emergence



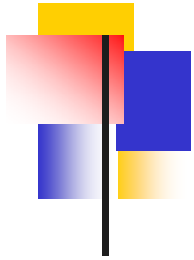
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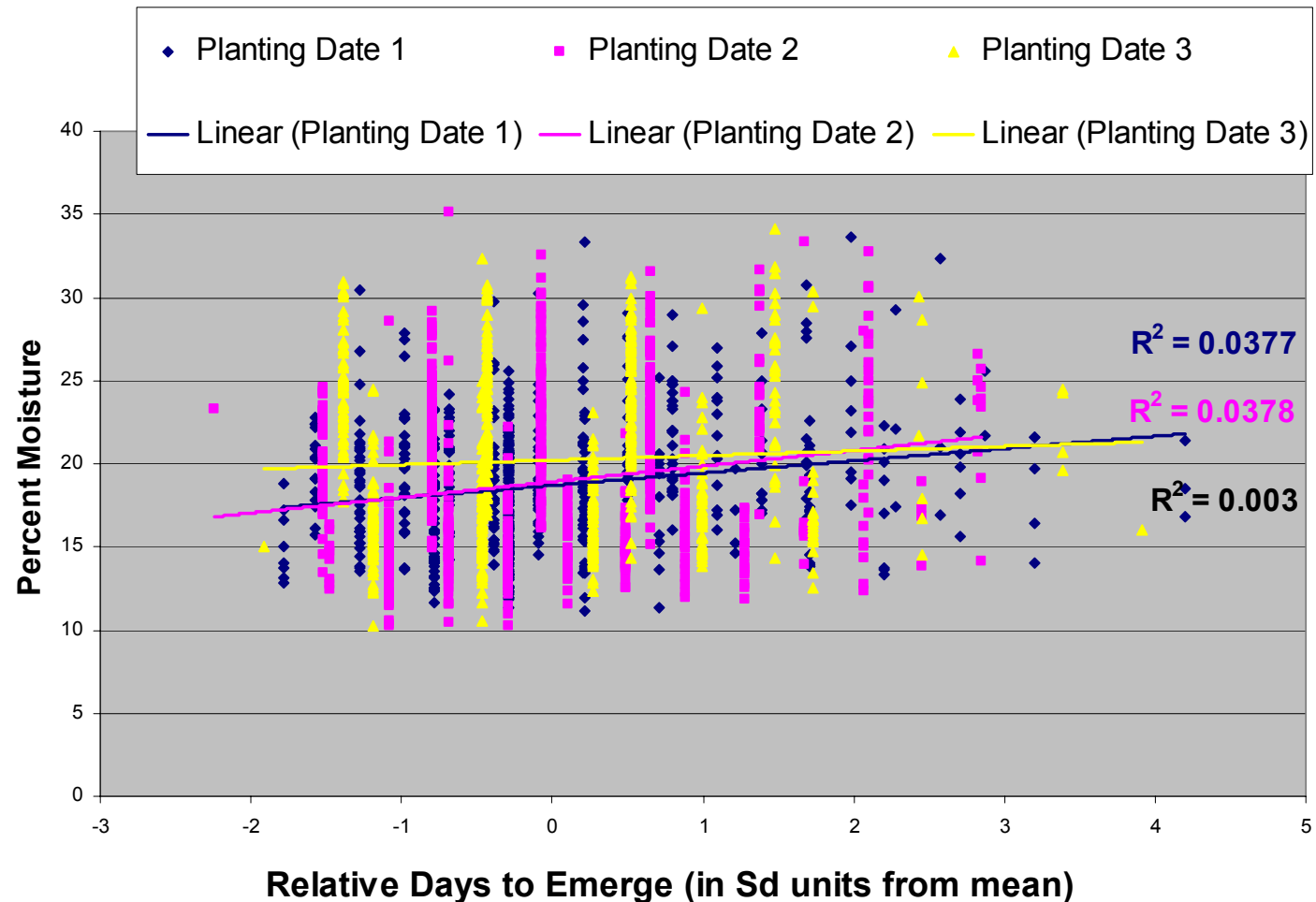
Yield vs. Relative Plant Spacing



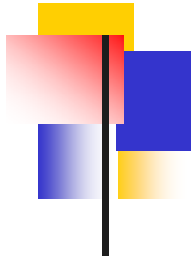
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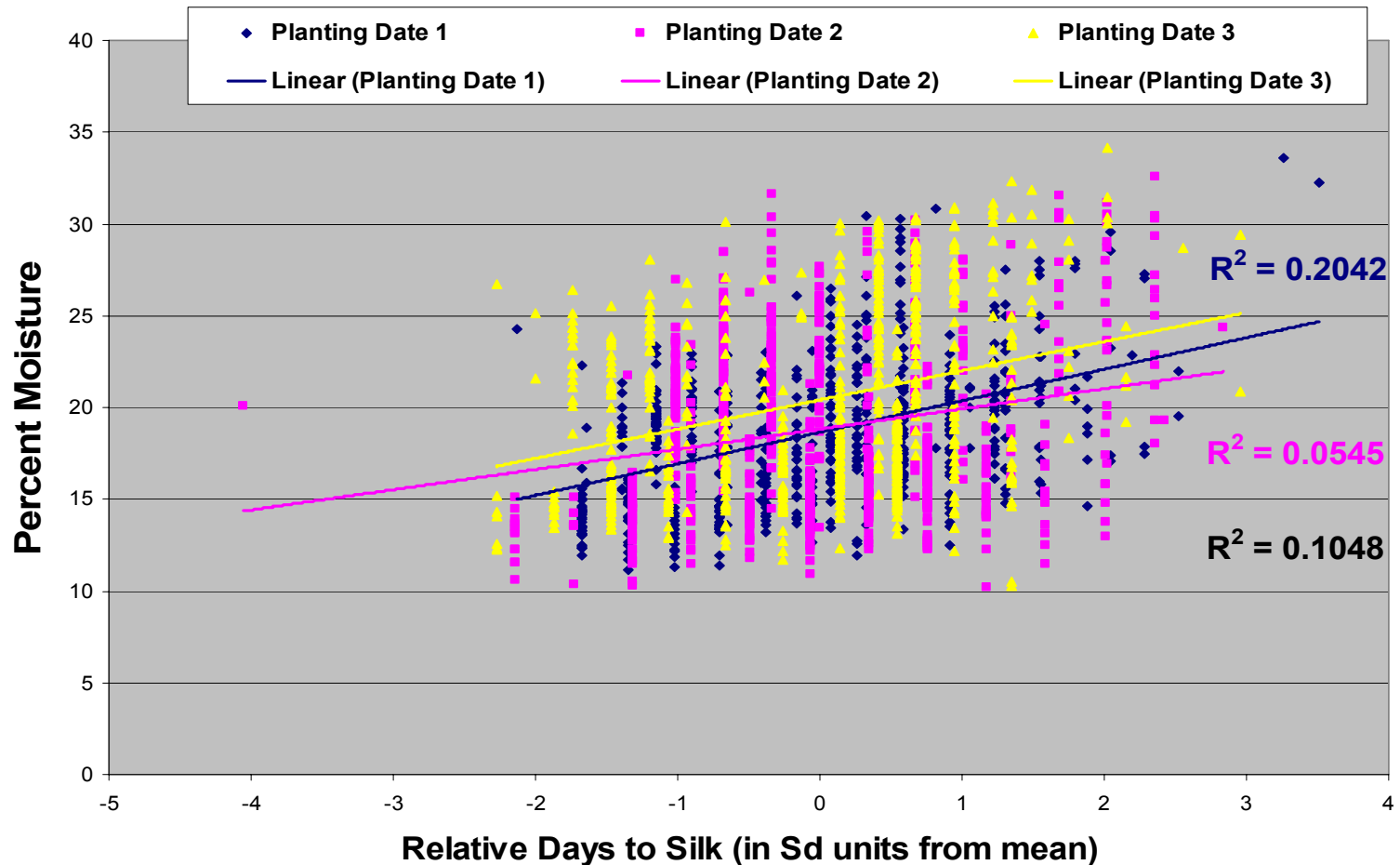
Plant Grain Moisture vs. Relative Emergence



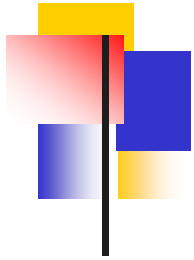
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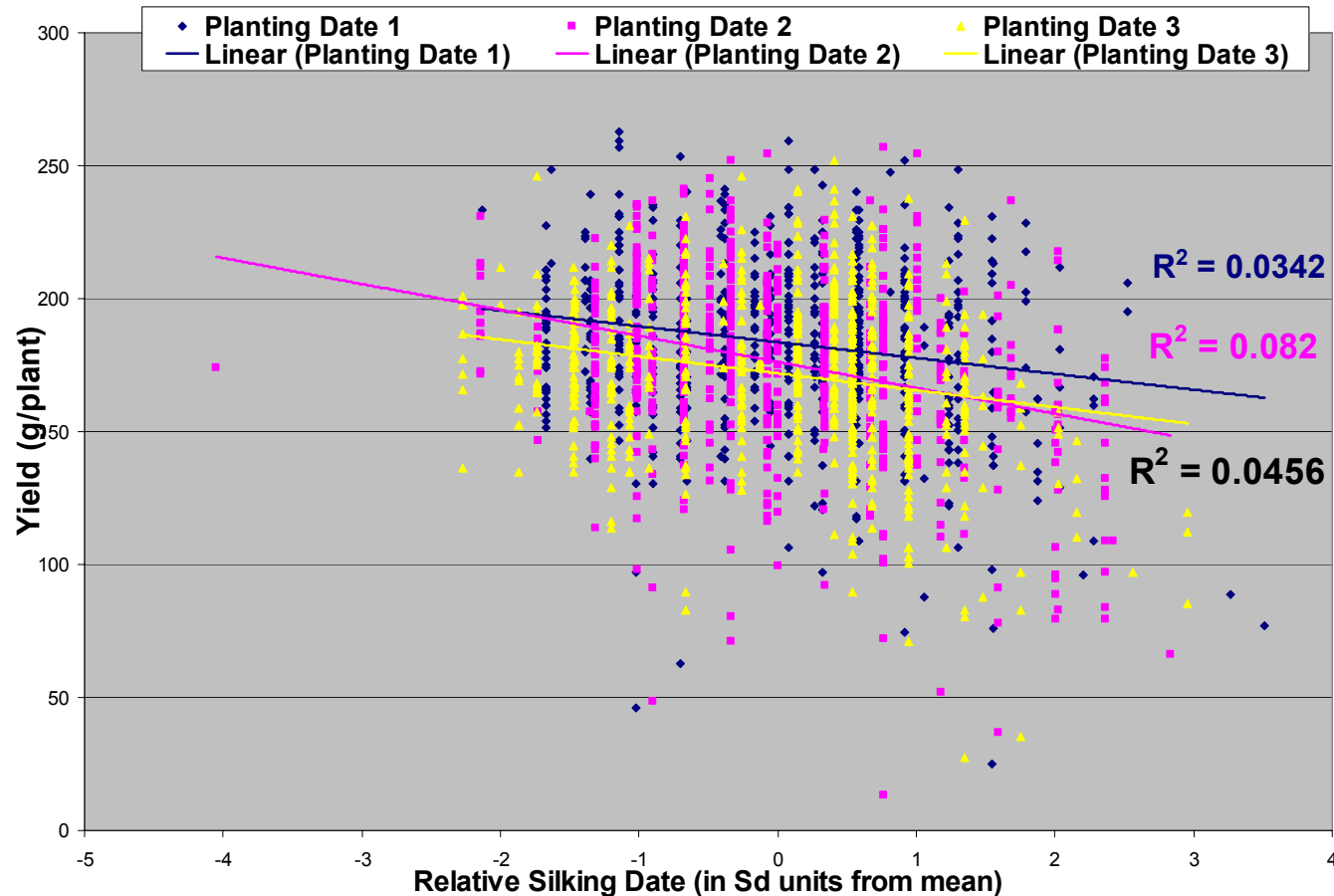
Grain Moisture vs. Relative Time to Silk



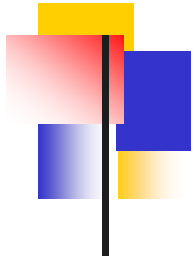
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Individual Grain Yield vs. Relative Silking



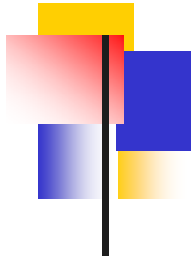
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Consistency of Resource Availability in High Population Environments ?



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Tentative Conclusions:

**For consistent individual ear weights
and high yields we need to make sure
“No Plant Left Behind!”**

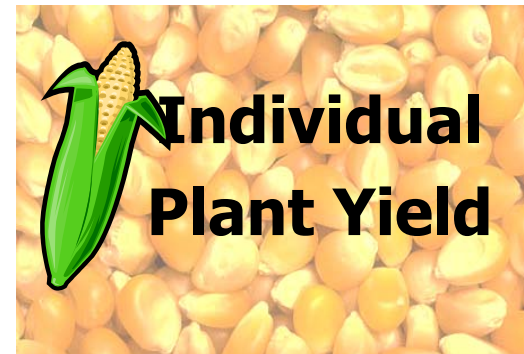
-

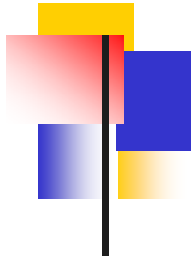
Emergence date

Effect

+

Silking Date & Plant Height

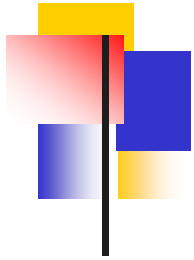




Implications:

- **Concern for emergence uniformity is overrated!**
- Although uniform seeding depth and seed placement are still desirable, it is more important to establish environments which lead to uniform growth and development of adjacent plants after emergence.
- **What can be done to insure all plants have uniform access to resources within the row?**





Acknowledgments



- **Purdue Research Foundation & Agricultural Research Programs**
- **Landec Ag (Monticello and Oxford, Indiana)**
- **John Deere Ltd. (Cropping Systems)**
- **Technical assistants and farm superintendents**

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